

<b>Notice of References Cited</b>	Application/Control No. 10/501,802	Applicant(s)/Patent Under Reexamination SMAHL, JARMO	
	Examiner David E. Bochna	Art Unit 3679	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,533,326	03-2003	Socier et al.	285/55
*	B	US-6,220,634	04-2001	Burrowes, Anh Tran	285/133.11
*	C	US-5,743,569	04-1998	Deters et al.	285/3
*	D	US-5,507,532	04-1996	Mitsui, Kenichi	285/61
*	E	US-5,411,300	05-1995	Mitsui, Kenichi	285/294.1
*	F	US-5,299,839	04-1994	Mogavero, Cesare	285/110
*	G	US-5,007,666	04-1991	Kyfes, Vincent	285/373
*	H	US-4,717,182	01-1988	Behrens et al.	285/230
*	I	US-4,681,349	07-1987	Press et al.	285/55
*	J	US-4,676,532	06-1987	Gronau et al.	285/133.5
*	K	US-4,036,513	07-1977	Loftus et al.	285/179
*	L	US-2,769,647	11-1956	HARSTICK WILLIAM H; et. al.	285/31
*	M	US-2,757,023	07-1956	HEIN HAROLD W	285/31

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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